







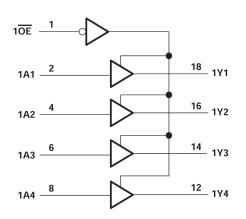
**SN74ACT244-Q1** 

SCAS766C - APRIL 2004 - REVISED JULY 2023

## SN74ACT244-Q1 Automotive Octal Buffer/Driver with 3-State Outputs

#### 1 Features

- Qualified for automotive applications
- Operation of 4.5-V to 5.5-V V<sub>CC</sub>
- Inputs accept voltages to 5.5 V
- Max t<sub>pd</sub> of 9 ns at 5 V
- Inputs are TTL-compatible



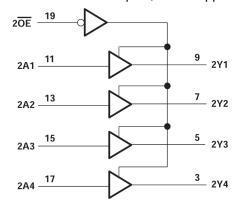
## 2 Description

This octal buffer/driver is designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and busoriented receivers and transmitters.

#### **Package Information**

PART NUMBER	PACKAGE <sup>1</sup>	PACKAGE SIZE <sup>2</sup>				
	DW (SOIC, 20)	12.8 mm × 10.3 mm				
SN74ACT244-Q1	PW (TSSOP, 20)	6.5 mm × 4.4 mm				
	RKS (VQFN, 20)	4.5 mm × 2.5 mm				

- 1. For all available packages, see the package option addendum at the end of the data sheet.
- 2. The package size (length × width) is a nominal value and includes pins, where applicable.





## **Table of Contents**

1 Features	1	7 Detailed Description	7
2 Description	1	7.1 Overview	
3 Revision History	2	7.2 Functional Block Diagram	7
4 Pin Configuration and Functions		7.3 Device Functional Modes	7
5 Specifications	4	8 Device and Documentation Support	8
5.1 Absolute Maximum Ratings		8.1 Documentation Support (Analog)	
5.2 ESD Ratings		8.2 Receiving Notification of Documentation Updates	
5.3 Recommended Operating Conditions		8.3 Support Resources	
5.4 Thermal Information	4	8.4 Trademarks	
5.5 Electrical Characteristics	<mark>5</mark>	8.5 Electrostatic Discharge Caution	8
5.6 Switching Characteristics	<mark>5</mark>	8.6 Glossary	
5.7 Operating Characteristics		9 Mechanical, Packaging, and Orderable Information	
6 Parameter Measurement Information		, , ,	

## **3 Revision History**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

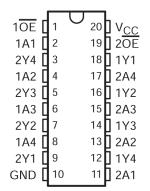
## Changes from Revision B (January 2008) to Revision C (July 2023)

Page

- Added Package Information table, Pin Functions table, ESD Ratings table, Thermal Information table, Device Functional Modes, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section



## **4 Pin Configuration and Functions**





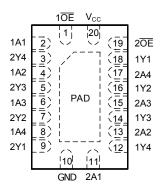


Figure 4-2. RKS Package (Top View)

**Table 4-1. Pin Functions** 

PIN		I/O	DESCRIPTION
NO.	NAME	1/0	DESCRIPTION
1	1 OE	I	Output Enable 1
2	1A1	I	1A1 Input
3	2Y4	0	2Y4 Output
4	1A2	I	1A2 Input
5	2Y3	0	2Y3 Output
6	1A3	I	1A3 Input
7	2Y2	0	2Y2 Output
8	1A4	I	1A4 Input
9	2Y1	0	2Y1 Output
10	GND	_	Ground pin
11	2A1	I	2A1 Input
12	1Y4	0	1Y4 Output
13	2A2	I	2A2 Input
14	1Y3	0	1Y3 Output
15	2A3	I	2A3 Input
16	1Y2	0	1Y2 Output
17	2A4	I	2A4 Input
18	1Y1	0	1Y1 Output
19	2 OE	I	Output Enable 2
20	VCC	_	Power Pin



## **5 Specifications**

## 5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range		-0.5	7	V
V <sub>I</sub> <sup>2</sup>	Input voltage range		-0.5	V <sub>CC</sub> + 0.5	V
V <sub>O</sub> <sup>2</sup>	Output voltage range		-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Input clamp current	(V <sub>I</sub> < 0 or V <sub>I</sub> > V <sub>CC</sub> )		±20	mA
I <sub>OK</sub>	Output clamp current	$(V_O < 0 \text{ or } V_O > V_{CC})$		±20	mA
Io	Continuous output current	$(V_O = 0 \text{ to } V_{CC})$		±50	mA
	Continuous current through V <sub>CC</sub> or GND			±200	mA
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### 5.2 ESD Ratings

			VALUE	UNIT
V (ESD)	Electrostatic discharge	Human body model (HBM), per AEC Q100-002 <sup>(1)</sup>	±2000	V
	Electrostatic discharge	Charged device model (CDM), per AEC Q100-011	±1000	<b>V</b>

<sup>(1)</sup> AEC Q100-002 indicates that HBM stressing must be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

## **5.3 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted)(1)

		·	MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage	4.5	5.5	V	
V <sub>IH</sub>	High-level input voltage		2		V
VIL	Low-level input voltage			0.8	V
VI	Input voltage			V <sub>CC</sub>	V
Vo	Output voltage		0	V <sub>CC</sub>	V
I <sub>OH</sub>	High-level output current			-24	mA
I <sub>OL</sub>	Low-level output current			24	mA
Δt/Δν	Input transition rise or fall rate			8	ns/V
т.	Operating free-air temperature	SN74ACT244I	-40	85	°C
IA	Operating nee-an temperature	SN74ACT244Q	-40	125	C

<sup>(1)</sup> All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

#### **5.4 Thermal Information**

		SN74AC	T244-Q1	
	THERMAL METRIC(1)	PW	RKS	UNIT
		20 PINS	20 PINS	
R <sub>θJA</sub> Junction-to-ambient thermal resistance		83	67.7	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

<sup>(2)</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

#### 5.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V <sub>cc</sub>	T <sub>A</sub> = 25°C			MIN MAX	MAY	UNIT
PARAIVIETER	TEST CONDITIONS		MIN	TYP	MAX	IVIIIN	MAX	UNII
	I <sub>OH</sub> = -50μA	4.5 V	4.4	4.49		4.4		
	10Η30μΑ	5.5 V	5.4	5.49		5.4		
V <sub>OH</sub>	I = -24 mA	4.5 V	3.86			3.76		V
	I <sub>OH</sub> = −24 mA	5.5 V	4.86	,		4.76		
	$I_{OH} = -75 \text{ mA}^{(1)}$	5.5 V				3.85		
	I <sub>OL</sub> = 50μA	4.5 V		0.001	0.1		0.1	
	10L - 30μΑ	5.5 V		0.001	0.1		0.1	
V <sub>OL</sub>	I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.44	V
	10L - 24 IIIA	5.5 V		,	0.36		0.44	
	I <sub>OL</sub> = 75 mA <sup>(1)</sup>	5.5 V					1.65	
I <sub>OZ</sub>	V <sub>O</sub> = V <sub>CC</sub> or GND	5.5 V			±0.25		±2.5	μA
I <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1		±1	μA
I <sub>CC</sub>	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		40	μA
Δl <sub>CC</sub> <sup>(2)</sup>	One input at 3.4 V, Other inputs at GND or V <sub>CC</sub>	5.5 V		0.6			1.5	mA
C <sub>i</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		2.5				pF
Co	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		8				pF

<sup>(1)</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

## **5.6 Switching Characteristics**

over recommended operating free-air temperature range,  $V_{CC}$  = 5 V ± 0.5 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T <sub>A</sub> = 25°C			MIN	MAX	UNIT
PARAMETER		TO (OUTPUT)	MIN	TYP	MAX	IVIIIN	WAX	UNII
t <sub>PLH</sub>	А	V	2	6.5	9	1.5	10	ns
t <sub>PHL</sub>		I I	2	7	9	1.5	10	
t <sub>PZH</sub>	- <del>OE</del>	V	1.5	7	8.5	1	9.5	no
t <sub>PZL</sub>	OE	ľ	2	7	9.5	1.5	10.5	ns
t <sub>PHZ</sub>	ŌĒ	V	2	8	9.5	1.5	10.5	ne
t <sub>PLZ</sub>	OL OL	ı	2.5	7.5	10	2	10.5	ns

## **5.7 Operating Characteristics**

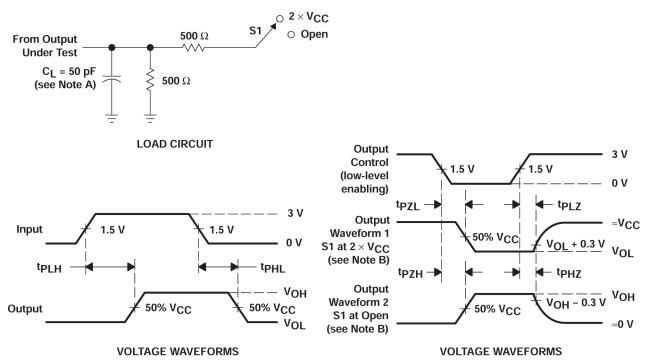
 $V_{CC}$  = 5 V,  $T_A$  = 25°C

	PARAMETER	TEST CONDITIONS	TYP	UNIT
$C_{pd}$	Power dissipation capacitance per buffer/driver	C <sub>L</sub> = 50 pF, f = 1 MHz	45	pF

<sup>(2)</sup> This is the increase in supply current for each input that is at one of the specified TTL voltage levels, rather than 0 V or V<sub>CC</sub>.



#### **6 Parameter Measurement Information**



- A. C<sub>L</sub> includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O$  = 50  $\Omega$ ,  $t_r \leq$  2.5 ns,  $t_f \leq$  2.5 ns.
- D. The outputs are measured one at a time, with one input transition per measurement.

Figure 6-1. Load Circuit and Voltage Waveforms

TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	2 × V <sub>CC</sub>
t <sub>PHZ</sub> /t <sub>PZH</sub>	Open

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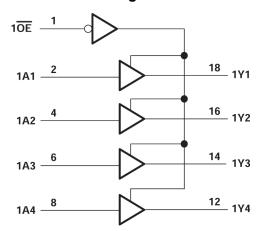
## 7 Detailed Description

### 7.1 Overview

The SN74ACT244 device is organized as two 4-bit buffers/drivers with separate output-enable  $(\overline{OE})$  inputs. When  $\overline{OE}$  is low, the device passes noninverted data from the A inputs to the Y outputs. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  shall be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

#### 7.2 Functional Block Diagram



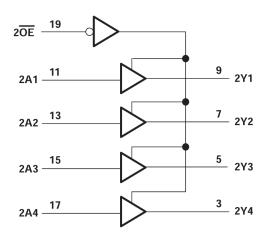


Figure 7-1. Logic Diagram (Positive Logic)

#### 7.3 Device Functional Modes

**Table 7-1. Function Table (Each Buffer)** 

INP	JTS	OUTPUT Y				
OE	Α	COIFOII				
L	Н	Н				
L	L	L				
Н	Х	Z				



## **8 Device and Documentation Support**

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

#### 8.1 Documentation Support (Analog)

#### 8.1.1 Related Documentation

How do I debounce a switch?

How do I redrive a digital signal for improved signal integrity?

How do I drive a transmission line with good signal integrity

## 8.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 8.3 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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#### 8.4 Trademarks

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#### 8.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 8.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.



## 9 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
		<b></b>				5 110 0 0	(6)				
SN74ACT244IPWRG4Q1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	ACT244I	Samples
SN74ACT244IPWRQ1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	ACT244I	Samples
SN74ACT244QWRKSRQ1	ACTIVE	VQFN	RKS	20	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	ACT244Q	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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## **PACKAGE OPTION ADDENDUM**

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF SN74ACT244-Q1:

Catalog : SN74ACT244

● Enhanced Product : SN74ACT244-EP

Military: SN54ACT244

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

• Enhanced Product - Supports Defense, Aerospace and Medical Applications

• Military - QML certified for Military and Defense Applications

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 7-Aug-2023

### TAPE AND REEL INFORMATION





	-
A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74ACT244IPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74ACT244IPWRQ1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.1	1.6	8.0	16.0	Q1
SN74ACT244QWRKSRQ1	VQFN	RKS	20	3000	180.0	12.4	2.8	4.8	1.2	4.0	12.0	Q1

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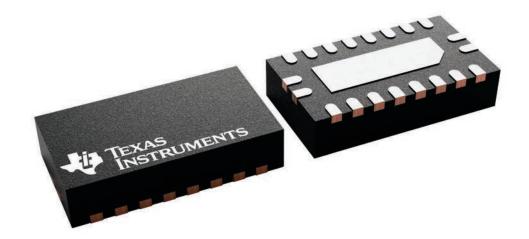
#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins SPQ		Length (mm)	Width (mm)	Height (mm)	
SN74ACT244IPWRG4Q1	TSSOP	PW	20	2000	356.0	356.0	35.0	
SN74ACT244IPWRQ1	TSSOP	PW	20	2000	356.0	356.0	35.0	
SN74ACT244QWRKSRQ1	VQFN	RKS	20	3000	210.0	185.0	35.0	

2.5 x 4.5, 0.5 mm pitch

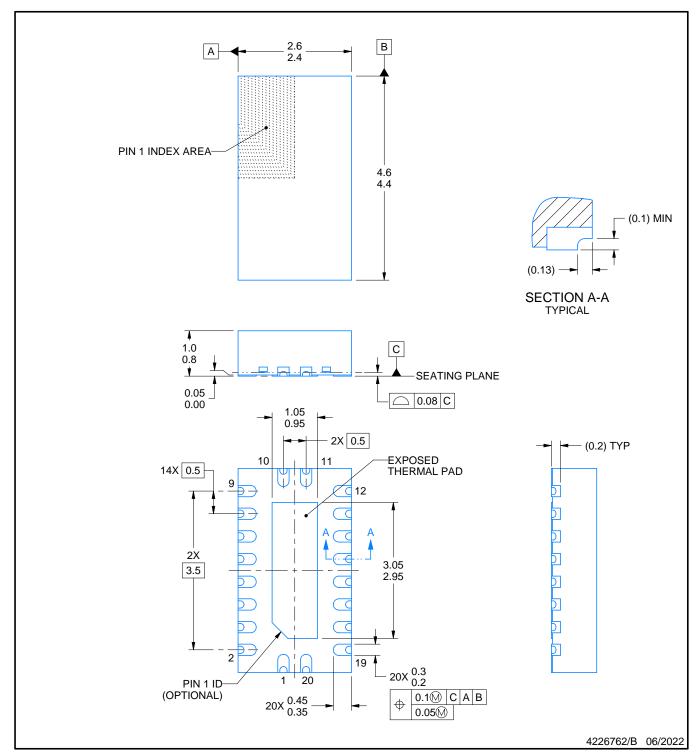
PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





PLASTIC QUAD FLATPACK - NO LEAD



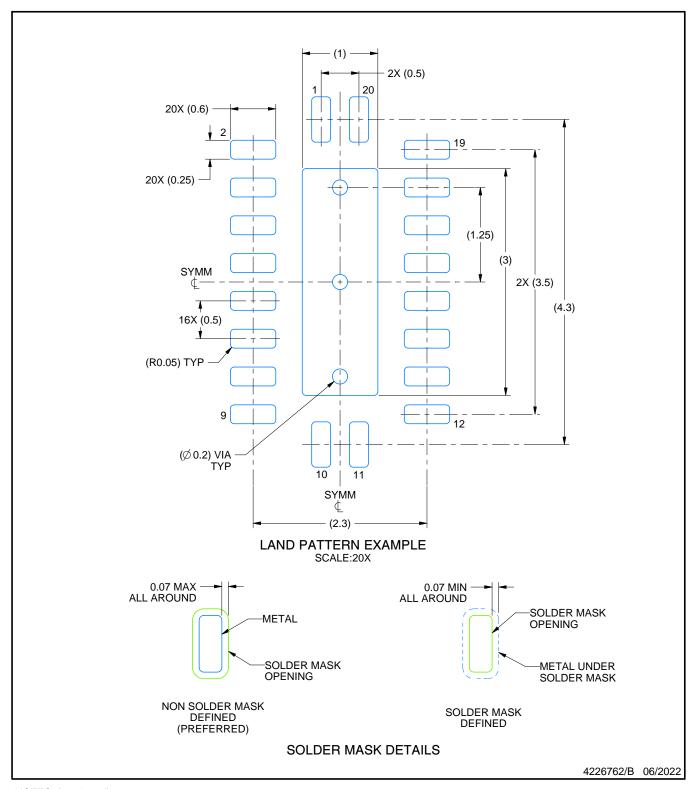
#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

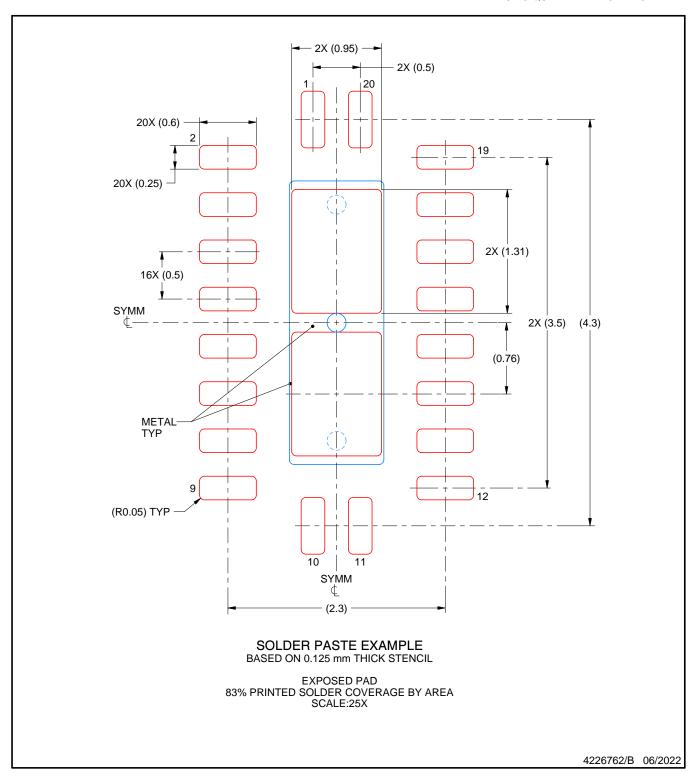


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If some or all are implemented, recommended via locations are shown.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





SMALL OUTLINE PACKAGE



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# PW (R-PDSO-G20)

## PLASTIC SMALL OUTLINE



NOTES:

- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
  C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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